

**Department of Mechanical Engineering
Indian Institute of Technology, Kanpur**

IITK/ME/2012-2013 /SB/ 05

Date: 03-09-12

Sealed Quotation for following term:

Opening date: 04-09-12

closing date: 12/09/2012

Subject: Purchase of UV- VIS Spectrometer

The detailed specifications that are needed for this purchase are mentioned below.

Double Beam 75 mm Integrating Sphere Accessory used for diffuse transmittance measurements of translucent, scattering or transparent solids, liquids, suspensions and solutions used for total or diffuse reflectance measurements and color determination of opaque solids.

Capability of measuring Reflectance of samples measured horizontally outside the sample compartment allowing large or delicate samples to be measured with ease ~ CIE, HAZE and UPF determination, compliant with Port Fraction of 3.6% (reflectance), 2.9% (transmittance) Integrating Sphere made of Spectralon® Measurement range of 220 - 850 nm ~ Hemispherical angle of incidence for reflection measurements (8°) ~ Reflectance Port diameter 14.3 mm (0.563 in) ~ Transmission Port diameter 14.3 mm (0.563 in)

Must Include: ~ All hardware for alignment, adjustment, and maintenance of the accessory ~ One uncalibrated Spectralon disk for baseline and transmission measurements.

Send sealed quotations to the following addressee:

Dr. Shantanu Bhattacharya (Ph.D.)
Associate Professor
Department of Mechanical Engineering
Indian Institute of Technology, Kanpur